MOSFET - Symmetrical Dual N-Channel 80 V, 18 mΩ, 26 A

NTTFD018N08LC

General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q2) and synchronous (Q1) have been designed to provide optimal power efficiency.

Features

Q1: N-Channel

- Max $r_{DS(on)} = 18 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 7.8 \text{ A}$
- Max $r_{DS(on)} = 29 \text{ m}\Omega$ at $V_{GS} = 4.5$, $I_D = 6.2 \text{ A}$

Q2: N-Channel

- Max $r_{DS(on)} = 18 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 7.8 \text{ A}$
- Max $r_{DS(on)} = 29 \text{ m}\Omega$ at $V_{GS} = 4.5$, $I_D = 6.2 \text{ A}$
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- RoHS Compliant

Typical Applications

- 48 V Input Primary Half Bridge
- Communications
- General Purpose Point of Load

PIN DESCRIPTION

Pin	Name	Description
1, 11, 12	GND (LSS)	Low Side Source
2	LSG	Low Side Gate
3, 4, 5, 6	V + (HSD)	High Side Drain
7	HSG	High Side Gate
8, 9, 10	SW	Switching Node, Low Side Drain

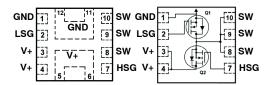


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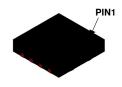
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
80 V	18 mΩ @ 10 V	26 A
	29 mΩ @ 4.5 V	21 A

ELECTRICAL CONNECTION



Dual N-Channel MOSFET





Top

Bottom

Power Clip 33 Symmetric (WQFN12) CASE 510CJ

MARKING DIAGRAM

D018 AYWWZZ

D018 = Specific Device Code
A = Assembly Plant Code
Y = Numeric Year Code
WW = Work Week Code
ZZ = Assembly Lot Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ORDERING INFORMATION AND PACKAGE MARKING

Device	Marking	Package	Shipping [†]
NTTFD018N08LC	D018	WQFN12 (Pb-Free)	3000 Units/ Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MOSFET MAXIMUM RATINGS (T_A = 25°C, Unless otherwise specified)

Symbol		Paran	neter		Q1	Q2	Units	
V_{DS}	Drain to Source	Voltage			80	80	V	
V_{GS}	Gate to Source \	/oltage			±20	±20	V	
I _D	Drain Current	-Continuous	T _C = 25°C	(Note 4)	26	26	Α	
		-Continuous	T _C = 100°C	(Note 4)	16	16		
		-Continuous	T _A = 25°C		6 (Note 1a)	6 (Note 1b)		
		-Pulsed	T _A = 25°C		349	349		
E _{AS}	Single Pulse Ava	alanche Energy (L = 1 m	H, I _{L(pk)} = 8 A)	(Note 3)	32	32	mJ	
P_{D}	Power Dissipation	n for Single Operation	T _C = 25°C		26	26	W	
	Power Dissipation	n for Single Operation	T _A = 25°C		1.7 (Note 1a)	1.7 (Note 1b)		
I _S	Source Current (Body Diode)			21	21	Α	
T _J , T _{STG}	Operating and S	torage Junction Tempera	ature Range		–55 to	-55 to +150		
TL	Lead Temperatu	re for Soldering Purpose	es (1/8" from case for 10 s)		260	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Q1	Q2	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.8	4.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	70 (Note 1a)	70 (Note 1b)	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	135 (Note 1c)	135 (Note 1c)	

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min.	Тур.	Max.	Units		
OFF CHAR	OFF CHARACTERISTICS								
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q1	80			V		
		$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$	Q2	80					
	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C	Q1		76.81		mV/°C		
		I _D = 250 μA, referenced to 25°C	Q2		76.81]		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 64 V, V _{GS} = 0 V	Q1			1	μΑ		
		V _{DS} = 64 V, V _{GS} = 0 V	Q2			1			
I _{GSS}	Gate to Source Leakage Current, Forward	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q1			±100	μΑ		
		$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q2			±100			

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

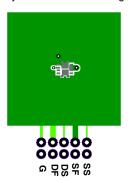
Symbol	Parameter	Test Conditions	Type	Min.	Тур.	Max.	Units
ON CHAR	ACTERISTICS						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 44 \mu A$	Q1	1.0	1.5	2.5	V
		$V_{GS} = V_{DS}$, $I_D = 44 \mu A$	Q2	1.0	1.5	2.5	5
	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 44 μA, referenced to 25°C	Q1		-5.71		mV/°C
		I _D = 44 μA, referenced to 25°C	Q2		-5.71		1
r _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10 V, I _D = 7.8 A	Q1		15	18	mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 6.2 \text{ A}$			22	29	
		$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A}, T_J = 125^{\circ}\text{C}$			25		
r _{DS(on)}	Drain to Source On Resistance	V _{GS} = 10 V, I _D = 7.8 A	Q2		15	18	mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 6.2 \text{ A}$			22	29	
		V _{GS} = 10 V, I _D = 7.8 A, T _J = 125°C			25		
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 7.8 A	Q1		23		S
		V _{DS} = 5 V, I _D = 7.8 A	Q2		23		
DYNAMIC	CHARACTERISTICS	·					
C _{ISS}	Input Capacitance	Q1:	Q1		856		pF
	' '	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ Mhz}$	Q2		856		1
C _{OSS}	Output Capacitance	Q2:	Q1		230		pF
		V _{DS} = 40 V, V _{GS} = 0 V, f = 1 MHz	Q2		230		
C _{RSS}	Reverse Transfer Capacitance		Q1		10		pF
	·		Q2		10		
R _G	Gate Resistance	T _A = 25°C	Q1	0.1	0.5	2	Ω
_			Q2	0.1	0.5	2	
SWITCHIN	G CHARACTERISTICS		1				ı
td _(ON)	Turn – On Delay Time	Q1:	Q1		9.4		ns
		$V_{DD} = 40 \text{ V}, V_{GS} = 4.5 \text{ V},$ $I_{D} = 6.2 \text{ A}, R_{GEN} = 6 \Omega$	Q2		9.4		
t _r	Rise Time		Q1		5.8		ns
		Q2: V _{DD} = 40 V, V _{GS} = 4.5 V,	Q2		5.8		
t _{D(OFF)}	Turn – Off Delay Time	I_D = 6.2 A, R_{GEN} = 6 Ω	Q1		14.6		ns
			Q2		14.6		
t _f	Fall Time		Q1		5.5		ns
			Q2		5.5		1
Qg	Total Gate Charge	V _{GS} = 0V to 10 V	Q1		12.4		nC
			Q2		12.4		
Qg	Total Gate Charge	V _{GS} = 0V to 4.5 V	Q1		6.0		nC
Ü			Q2		6.0		
Q _{gs}	Gate to Source Gate Charge	Q1: V _{DD} = 40 V,	Q1	-	1.94		nC
-yə		I _D = 6.2 A Q2:	Q2		1.94		-
Q _{gd}	Gate to Drain "Miller" Charge	$V_{DD} = 40 \text{ V},$	Q1		1.71		nC
⊶gd	Gate to Drain Willer Charge	$I_D = 6.2 \text{ A}$					110
			Q2		1.71		

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

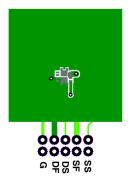
Symbol	Parameter	Test Conditions	Туре	Min.	Тур.	Max.	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS								
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 7.8 A (Note 2)	Q1		0.82	1.5	V	
		V _{GS} = 0 V, I _S = 7.8 A (Note 2)	Q2		0.82	1.5		
t _{rr}	Reverse Recovery Time Reverse Recovery Charge	Q1:	Q1		13.3		ns	
		I _F = 7.8 A, di/dt = 300 A/μs	Q2		13.3			
Q _{rr}		- Q2: I _F = 7.8 A, di/dt = 300 A/μs	Q1		18.1		nC	
			Q2		18.1			
t _{rr}	Reverse Recovery Time	Q1:	Q1		10.3		ns	
		I _F = 7.8 A, di/dt = 1000 A/μs	Q2		10.3			
Q _{rr}	Reverse Recovery Charge	- Q2: I _F = 7.8 A, di/dt = 1000 A/μs	Q1		51		nC	
			Q2		51			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 \times 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



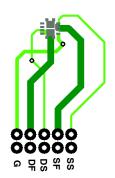
a) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



c) 135°C/W when mounted on a minimum pad of 2 oz copper.



d) 135°C/W when mounted on a minimum pad of 2 oz copper.

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
 Q1: E_{AS} of 32 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 8 A, V_{DD} = 80 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 8.2 A. Q2: E_{AS} of 32 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 8 A, V_{DD} = 80 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 8.2 A.
 Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal
- & electro-mechanical application board design.

TYPICAL CHARACTERISTICS

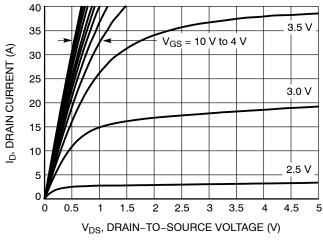


Figure 1. On-Region Characteristics

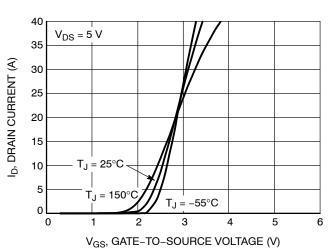


Figure 2. Transfer Characteristics

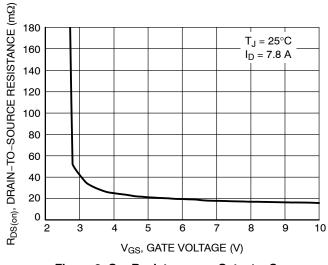


Figure 3. On-Resistance vs. Gate-to-Source Voltage

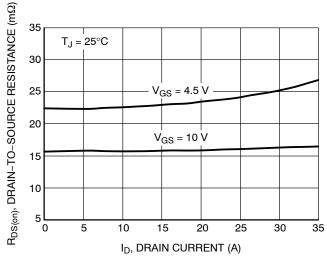


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

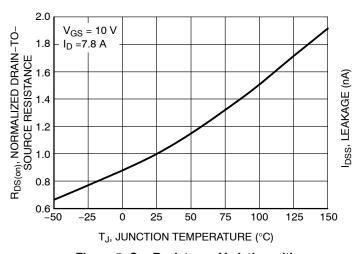


Figure 5. On–Resistance Variation with Temperature

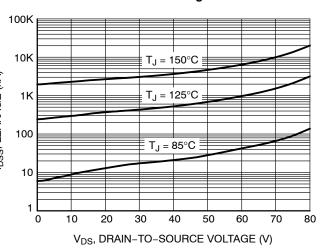


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

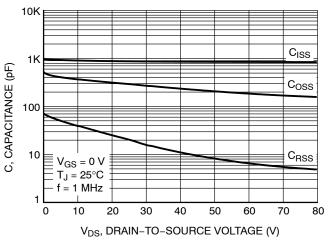


Figure 7. Capacitance Variation

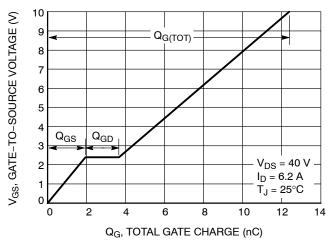


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

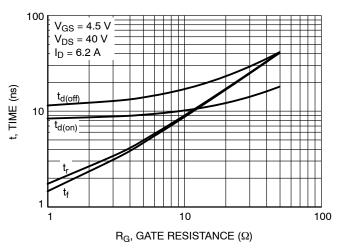


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

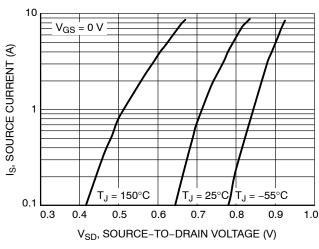


Figure 10. Diode Forward Voltage vs. Current

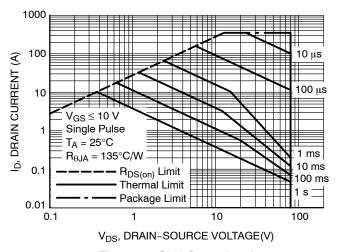


Figure 11. Safe Operating Area

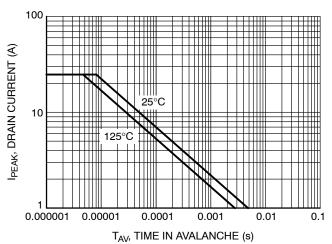


Figure 12. $I_{\mbox{\scriptsize PEAK}}$ vs. Time in Avalanche

TYPICAL CHARACTERISTICS

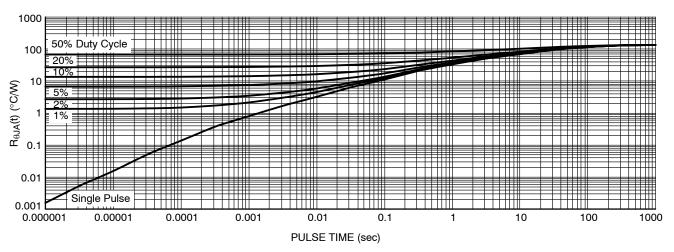
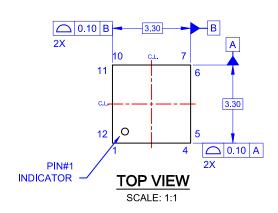
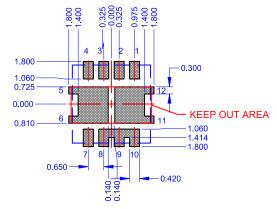


Figure 13. Thermal Characteristics

PACKAGE DIMENSIONS

WQFN12 3.3X3.3, 0.65PCASE 510CJ ISSUE O



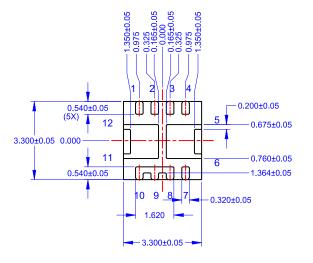


LAND PATTERN RECOMMENDATION

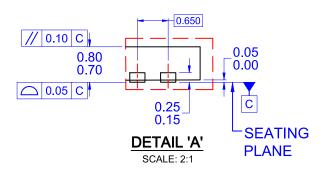
SCALE 1:1



FRONT VIEW SCALE: 1:1



BOTTOM VIEW SCALE: 1:1



NOTES: UNLESS OTHERWISE SPECIFIED

- A) DRAWING DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-220, VARIATION WEEC-1
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.

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